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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Kazuhito TANAKA et al.

Group Art Unit : Not Yet Assigned

Appl. No. : 10/567,357

(U.S. National Stage of PCT/JP2004/011504)

I.A. Filed : August 4, 2004

Examiner : Not Yet Assigned



For DISPLAY DEVICE

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
U.S. Patent and Trademark Office
Customer Service Window, Mail Stop AMENDMENT
Randolph Building
401 Dulany Street
Alexandria, VA 22314

Sir :

In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and §§1.97-1.98, Applicants hereby bring the following information to the attention of the Examiner in charge of the above-identified application, which includes information cited and discussed in the specification and the International Search Report issued in connection with International Patent Application No. PCT/JP2004/011504, of which the present application is the U.S. National Stage Application. A copy of the International Search Report was enclosed with the papers when entering the U.S. National Stage on February 6, 2006. The Examiner is requested to review these materials to inspect the relevance indicated during international examination with respect to the documents cited therein. The following is a list of the documents cited in the above-noted documents:

Japanese Laid-open Patent Publication No. 2002-156941, together with an English language Abstract of the same and patent family member U.S. Patent No. 6,559,603. Applicants note that the Japanese document is cited on page 1 of the specification of the above-captioned application;

Japanese Laid-open Patent Publication No. 2002-358044, together with an English language Abstract of the same, and patent family members U.S. Patent No. 6,927,751 and U.S. Patent Application Publication No. 2002/0180668;

Japanese Laid-open Patent Publication No. HEI 10-260653, together with an English language Abstract of the same; and

Japanese Laid-open Patent Publication No. HEI 10-232655, together with an English language Abstract of the same.

Applicants also call to the Examiner's attention the following documents:

Japanese Laid-open Patent Publication No. HEI 6-152567, together with an English language Abstract of the same;

Japanese Laid-open Patent Publication No. HEI 6-167946, together with an English language Abstract of the same;

U.S. Patent No. 6,462,721;

U.S. Patent No. 6,690,388; and

U.S. Patent Application Publication No. 2006/0038750.

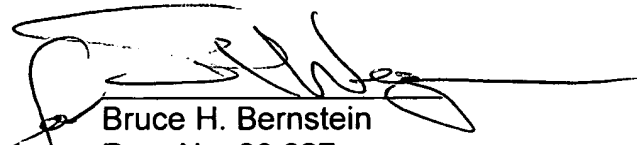
Further to 37 C.F.R. §1.98 (a)(2)(ii), copies of the U.S. patents and the U.S. patent application publications are not enclosed herewith. However, if copies are needed, the Examiner is respectfully requested to contact the undersigned.

Applicants respectfully request that the Examiner consider the above material and cite the same. Copies of the above-noted foreign documents are attached hereto and all of the above-noted documents are listed on the attached PTO-1449 Form. The Examiner is requested to initial the appropriate spaces on the attached Form and to return a copy of the completed Form to Applicant with the next official communication in the present application.

Applicants note that an Office Action on the merits has not issued in the present application, and thus, no fee is believed necessary to ensure consideration of the submitted material.

Should the Examiner have any questions, the Examiner is requested to contact the undersigned at the below-listed telephone number.

Respectfully Submitted,
Kazuhito TANAKA et al.



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FORM PTO-1449

U.S. Department of Commerce
Patent and Trademark OfficeAtty. Docket No.
P29233Application No.
10/567,357INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

Applicant
Kazuhito TANAKA et al.Filing Date
I.A. Filed August 4, 2004Group
Not Yet Assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	6 5 5 9 6 0 3	05/06/03	IWAMI			
	6 9 2 7 7 5 1	08/09/05	IDE et al.			
2002 /	0 1 8 0 6 6 8	12/05/02	IDE et al.			
	6 4 6 2 7 2 1	10/08/02	KASAHARA et al.			
	6 6 9 0 3 8 8	02/10/04	KASAHARA et al.			
2006 /	0 0 3 8 7 5 0	02/23/06	INOUE et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
2002	- 1 5 6 9 4 1	05/31/02	JAPAN			
2002	- 3 5 8 0 4 4	12/13/02	JAPAN			
10	- 2 6 0 6 5 3	09/29/98	JAPAN			
10	- 2 3 2 6 5 5	09/02/98	JAPAN			
6	- 1 5 2 5 6 7	05/31/94	JAPAN			
6	- 1 6 7 9 4 6	06/14/94	JAPAN			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

1	English Language Abstract of JP 2002-156941.
2	English Language Abstract of JP 2002-358044.
3	English Language Abstract of JP 10-260653.
4	English Language Abstract of JP 10-232655.
5	English Language Abstract of JP 6-152567.
6	English Language Abstract of JP 6-167946.

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.